



PATENT

Case Docket No. MICRON.061DV1

Date: March 19, 2001

Page 1

In re application of : Ahmad
App. No. : 09/397,952
Filed : September 17, 1999
For : FABRICATION OF
INTEGRATED DEVICES
USING NITROGEN
IMPLANTATION
Examiner : Stephen H. Rao
Art Unit : 2814

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on

March 19, 2001

(Date)
Adeel S. Akhtar
Adeel S. Akhtar, Reg. No. 41,349

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ASSISTANT COMMISSIONER FOR PATENTS BOX AF
WASHINGTON, D.C. 20231

Sir:

Transmitted herewith is an amendment in the above-identified application.

The fee has been calculated as shown below:

CLAIMS AS FILED						
	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NO. PREVIOUSLY PAID FOR	PRESENT EXTRA	RATE	ADDITIONAL FEE
Total Claims	21	—	21	= 0 ×	\$18	= \$0
Independent Claims	4	—	4	= 0 ×	\$80	= \$0
If application has been amended to contain multiple dependent claim(s), then add					\$270	= \$0
Time Extension Fee						\$0
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT						\$0

(X) Return prepaid postcard.

(X) Please charge any additional fees, including any fees for additional extension of time, or credit overpayment to Deposit Account No. 11-1410. A duplicate copy of this sheet is enclosed.

Adeel S. Akhtar
Adeel S. Akhtar
Registration No. 41,349
Attorney of Record

#71C
T. Young
3-27-01
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(Date) 12/12/2019
Adeel S. Akhtar
 Adeel S. Akhtar, Reg. No. 41,349

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Dear Sir:

In the Claims:

1. (Twice Amended) A process of forming a gate structure on a semiconductor substrate, comprising:

providing a semiconductor substrate having a channel region formed therein so as to define a source and a drain region and a gate structure comprised of a gate dielectric positioned on said channel region and a conductive layer positioned on said gate dielectric; forming an insulator element region directly on said substrate; and